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Page (#)

























Page (#)







DRAM chip type	DIMM Stick Type	Bus Clock Rate (MHz)	Memory Clock Rate (MHz)	Channel Bandwidth (GB/s)	non-ECC Channel Width	ECC Channel Width	Prefetch Buffer Width	Vdd	Read Latency Typical (bus cycles)	DIMM pins
DDR-200	PC-1600	100	100	1.6	64	72	2	2.5	2-3	184
DDR-266	PC-2100	133	133	2.133	64	72	2	2.5	2-3	184
DDR-333	PC-2700	167	167	2.667	64	72	2	2.5	2-3	184
DDR-400	PC3200	200	200	3.2	64	72	2	2.5	2-3	184
DDR2-400	PC2-3200	100	200	3.2	64	72	4	1.8	3-9	240
DDR2-533	PC2-4200	133	266	4.267	64	72	4	1.8	3-9	240
DDR2-667	PC2-5300	167	333	5.333	64	72	4	1.8	3-9	240
DDR2-800	PC2-6400	200	400	6.4	64	72	4	1.8	3-9	240
DDR3-800	PC3-6400	100	400	6.4	64	72	8	15	2	240
DDR3-1066	PC3-8500	133	533	8.53	64	72	8	1.5	?	240
DDR3-1333	PC3-10600	167	667	10.67	64	72	8	1.5	?	240
DDR3-1600	PC3-17000	200	1066	18.06	64	72	8	1.5	?	240